

Supplementary Information

Enhanced Catalytic Activity and Stability of SOFC Electrodes through Plasma-driven Surface Modification

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Table S1 The area intensity and ratio for X-ray photoelectron spectroscopy (XPS) spectra of Sr $3d_{5/2}$ and $3d_{3/2}$.

Sample	Intensity		Area ratio	Intensity		Area ratio
	Sr _(lattice) $3d_{5/2}$	Sr _(lattice) $3d_{3/2}$		Sr _(non-lattice) $3d_{5/2}$	Sr _(non-lattice) $3d_{3/2}$	
Bare	25864.4	17241.2	3:2	31040	20691.2	3:2
Plasma	25966.6	17309.3	3:2	18715.1	12475.5	3:2

Table S2 The deconvolution analysis areas for each peak.

Sample	O_{lattice}		O_{defect}		O_{surface}		H_2O_{ad}		Area ratio		
	BE	FWHM	BE	FWHM	BE	FWHM	BE	FWHM	O_{lattice}	O_{defect}	$O_{\text{defect}}/O_{\text{lattice}}$
Bare	528.56	1.10	529.4	2.08	531.35	1.74	533.3	1.96	72683.8	55923.6	0.77
Plasma	528.23	1.16	529.4	1.90	531.46	1.83	533.3	1.94	42516.9	47572.9	1.12

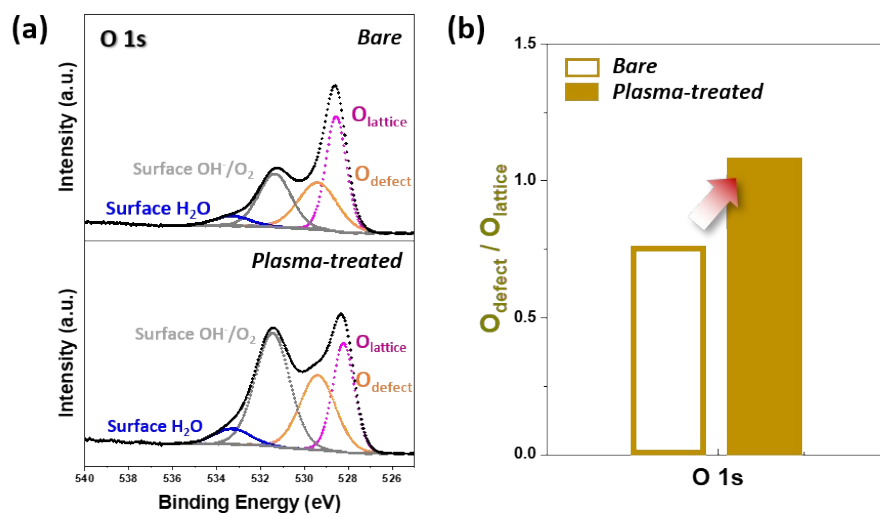


Fig. S1 X-ray photoelectron spectroscopy (XPS) results of (a) O 1s spectra, and (b) summarized graph of bare and plasma-treated $\text{La}_{0.6}\text{Sr}_{0.4}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ (LSCF) surfaces.

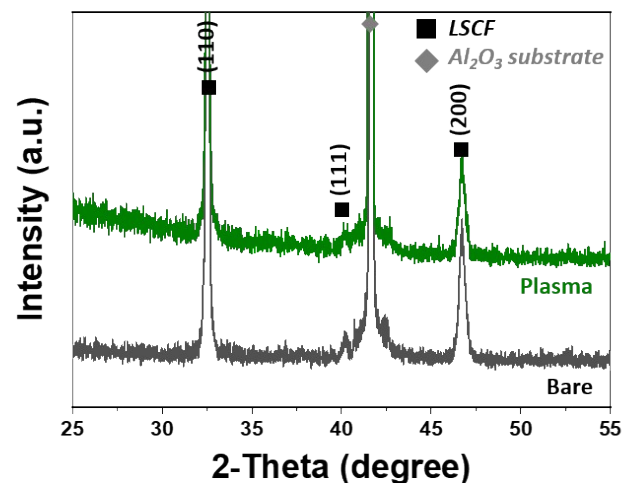


Fig. S2 X-ray diffraction (XRD) patterns of $\text{La}_{0.6}\text{Sr}_{0.4}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ (LSCF) films with plasma exposure.

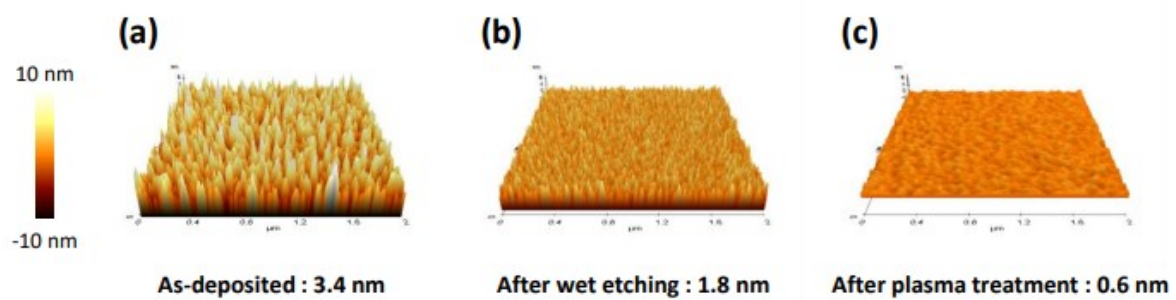


Fig. S3 Surface morphological changes of (a) as-deposited, (b) bare, and (c) plasma-treated $\text{La}_{0.6}\text{Sr}_{0.4}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ (LSCF) films by atomic force microscopy (AFM).

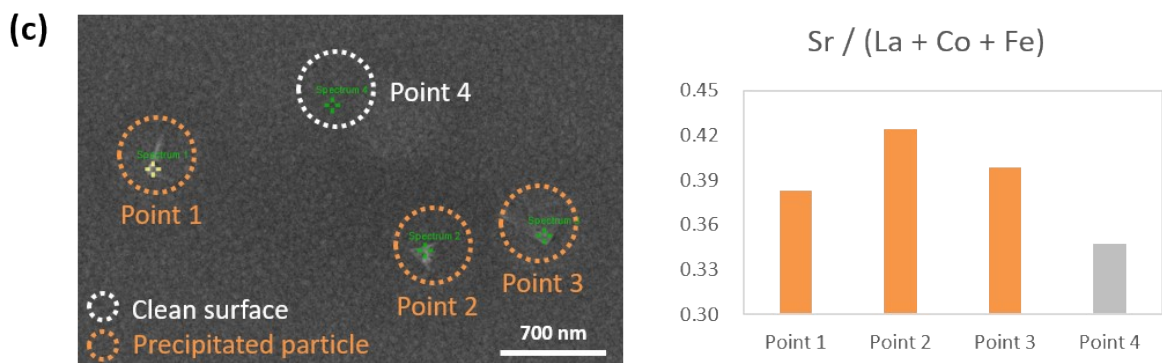
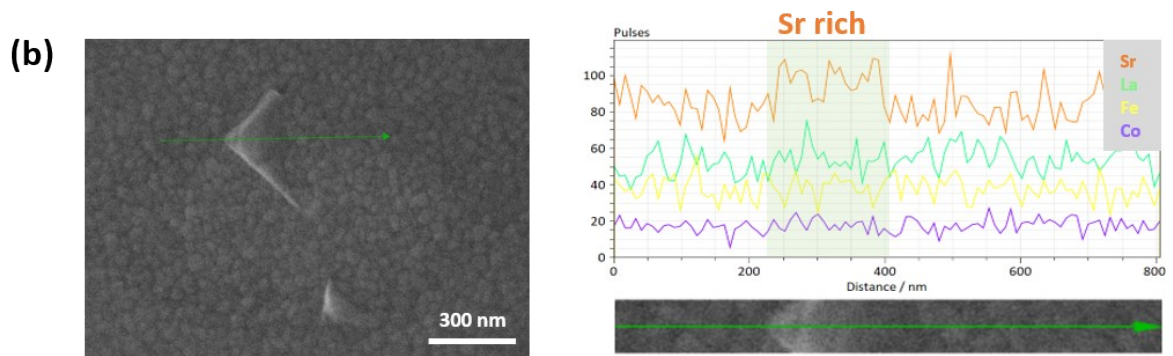
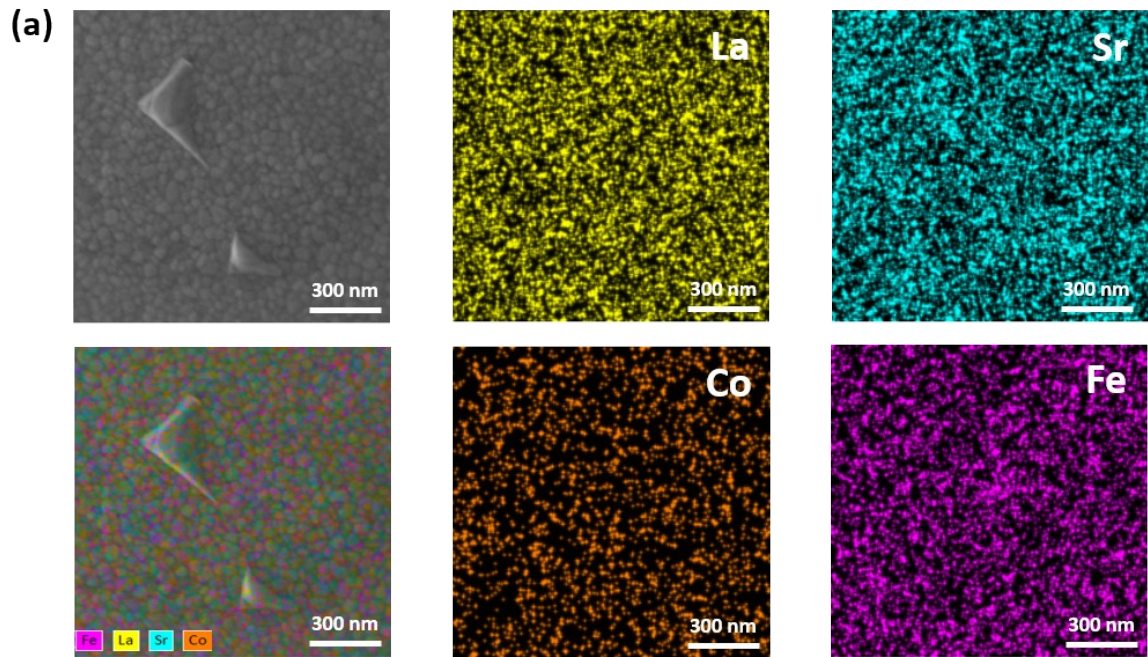


Fig. S4 Scanning electron microscopy (SEM) analysis of bare $\text{La}_{0.6}\text{Sr}_{0.4}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ (LSCF) thin films after heat treatment at 650 °C for 30 hours (a) energy-dispersive X-ray spectroscopy (EDS) elemental maps, (b) EDS line-scanning, and (c) EDS point analysis.

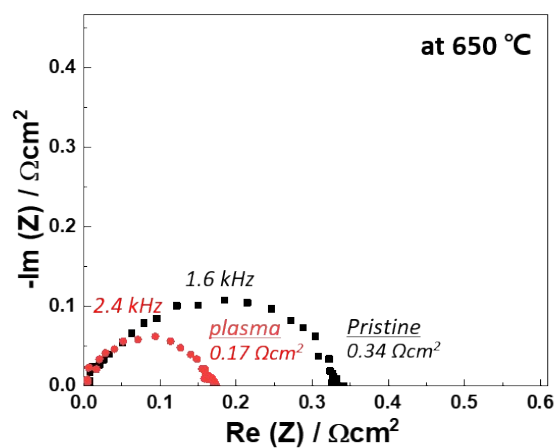


Fig. S5 Nyquist plots of pristine and plasma-treated $\text{La}_{0.6}\text{Sr}_{0.4}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ (LSCF) at 650 °C.

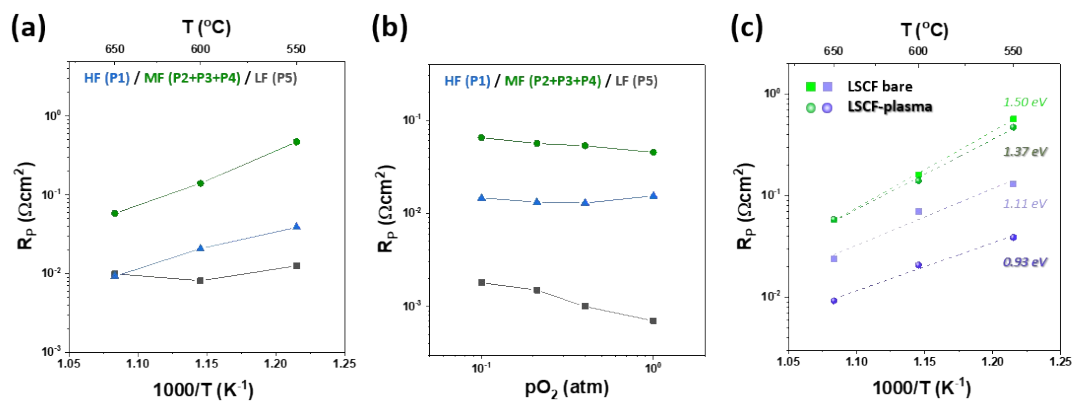


Fig. S6 (a) Temperature and (b) oxygen partial pressure dependencies results of plasma treated LSCF in different frequency region and (c) comparison of activation energy of medium frequency (MF) and high frequency (HF) resistance for bare and plasma-treated $\text{La}_{0.6}\text{Sr}_{0.4}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ (LSCF).

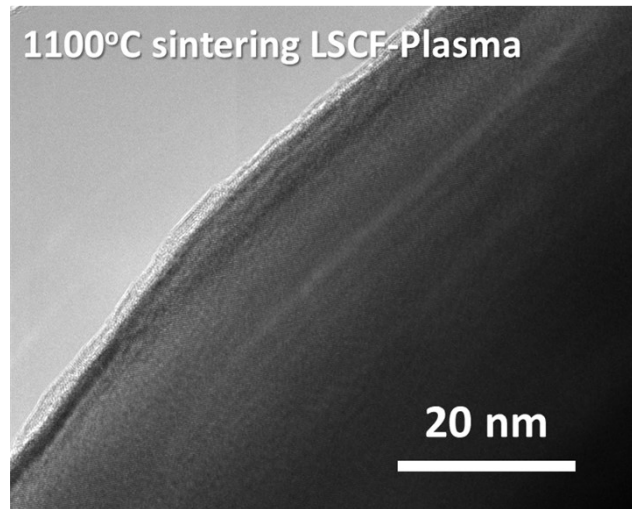


Fig. S7. HR-TEM image of 1100°C-sintered LSCF with plasma treatment